

Title (en)

METHOD AND APPARATUS FOR OPTICALLY CHARACTERIZING THE DOPING OF A SUBSTRATE

Title (de)

VERFAHREN UND VORRICHTUNG ZUR OPTISCHEN CHARAKTERISIERUNG EINER SUBSTRATDOTIERUNG

Title (fr)

MÉTHODE ET APPAREIL DE CARACTÉRISATION OPTIQUE DU DOPAGE D'UN SUBSTRAT

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Application

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Abstract (en)

[origin: WO2007144514A1] The invention relates to an optical characterization method that includes a step of evaluating the doping of a substrate (SUB) by means of a reflected beam coming from a light source, this method being carried out with an apparatus comprising: - this light source (LAS) for producing an incident beam (I) along an axis of incidence; - a first detector (DET1) for measuring the power of this reflected beam (R) along an axis of reflection, the axis of incidence and the axis of reflection intercepting at a measurement point and making a non-zero measurement angle (2T); and - a polarizer (POL) placed in the path of the incident beam (I). Furthermore the light source (LAS) is monochromatic. The invention also relates to an ion implanter equipped with this apparatus.

IPC 8 full level

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